







SN74LV138A SCLS395N - APRIL 1998 - REVISED MARCH 2023

SN74LV138A 3-Line to 8-Line Decoders or Demultiplexers

1 Features

- V_{CC} operation of 2 V to 5.5 V
- Maximum t_{pd} of 9.5 ns at 5 V
- Typical V_{OLP} (output ground bounce) <0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (output V_{OH} undershoot) $>2.3 \text{ V at V}_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- Support mixed-mode voltage operation on all ports
- I_{off} supports partial-power-down mode operation
- Latch-up performance exceeds 250 mA per JESD

2 Applications

- Output expansion
- LED matrix control
- 7-segment display control
- 8-bit data storage

3 Description

The SN74LV138A device is 3-line to 8-line decoders/ demultiplexers designed for 2 V to 5.5 V V_{CC} operation.

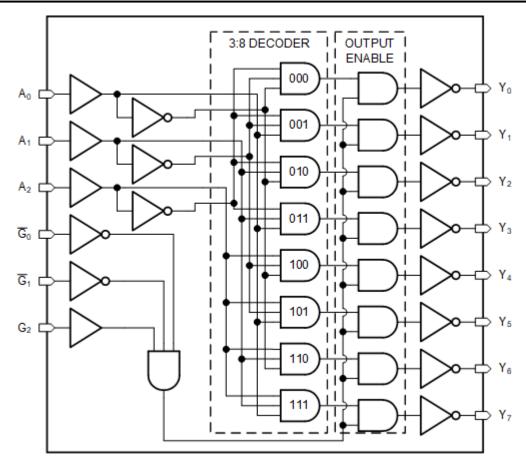
The conditions at the binary-select inputs (A_0, A_1, A_2) and the three enable inputs (G2, G0, G1) select one of eight output lines. The two active-low (G0, G1) and one active-high (G2) enable inputs reduce the need for external gates or inverters when expanding.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE		
	D (SOIC, 16)	9.90 mm × 3.91 mm		
	DB (SSOP, 16)	6.20 mm × 5.30 mm		
	DGV (TVSOP, 16)	3.60 mm × 4.40 mm		
SN74LV138A	NSA (BGA, 16)	2.00 mm × 2.00 mm		
	PW (TSSOP, 16)	5.00 mm × 4.40 mm		
	RGY (VQFN, 16)	4.00 mm × 3.50 mm		
	BQB (WQFN, 16)	3.60 mm × 2.60 mm		

For all available packages, see the orderable addendum at the end of the data sheet.





Logic Diagram (Positive Logic)



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4 Revision History Changes from Revision M (December 2022) to Revisi	on N (March 2023) Page
Updated the structural layout of document to current states.	· · · · · · · · · · · · · · · · · · ·
Changes from Revision L (August 2005) to Revision	M (December 2022) Page
	nd cross-references throughout the document to reflect
	-
Added the Applications section	
 Added the Device Information table and removed the 	Ordering Intermation table



5 Pin Configuration and Functions

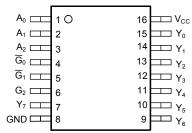


Figure 5-1. D, DB, DGV, NS and PW Package 16-Pin (Top View)

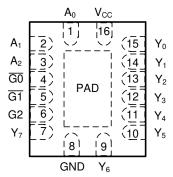


Figure 5-2. RGY and BQB Package 16-Pin (Top View)

Table 5-1. Pin Functions

	PIN	TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.	ITPE(")	DESCRIPTION
A ₀	1	I	Address select 0
A ₁	2	1	Address select 1
A ₂	3	1	Address select 2
G2	6	1	Strobe input
G0	4	I	Strobe input, active low
G1	5	I	Strobe input, active low
GND	8	G	Ground
V _{CC}	16	Р	Positive supply
Y ₀	15	0	Output 0
Y ₁	14	0	Output 1
Y ₂	13	0	Output 2
Y ₃	12	0	Output 3
Y ₄	11	0	Output 4
Y ₅	10	0	Output 5
Y ₆	9	0	Output 6
Y ₇	7	0	Output 7
Thermal Pad		-	Thermal Pad ⁽²⁾

- (1) Signal Types: I = Input, O = Output, I/O = Input or Output, G = Ground, P = Power
- (2) BQB and RGY package only



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

	1 3 1	·	MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
VI	Input voltage range ⁽²⁾		-0.5	7	V
Vo	oltage range applied to any output in the high-impedance or power-off state ⁽²⁾		-0.5	7	V
Vo	Output voltage range ^{(2) (3)}		-0.5	V _{CC} + 0.5	V
I _{IK}	Input clamp current	V _I < 0		-20	mA
I _{OK}	Output clamp current	V _O < 0		-50	mA
Io	Continuous output current	$V_O = 0$ to V_{CC}		±25	mA
	Continuous current through V _{CC} or GND			±50	mA
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

- (2) The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
- (3) This value is limited to 5.5 V maximum.

6.2 ESD Ratings

				VALUE	UNIT
Γ,	./	Electrostatic	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V
	V(ESD)	discharge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 ⁽²⁾	±1000	, v

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.3 Recommended Operating Conditions(1)

			SN74LV	138A	LINUT
			MIN	MAX	UNIT
V _{CC}	Supply voltage		2	5.5	V
		V _{CC} = 2 V	1.5		
\/	High level input voltage	V _{CC} = 2.3 V to 2.7 V	V _{CC} × 0.7		V
VIН	nigri-lever iriput voltage	V _{CC} = 3 V to 3.6 V	V _{CC} × 0.7		V
$V_{IH} \text{High-level input voltage} \begin{cases} V_{CC} = 2 \text{ V} \\ V_{CC} = 2.3 \text{ V to } \\ V_{CC} = 3 \text{ V to } 3. \\ V_{CC} = 2.3 \text{ V to } 3. \\ V_{CC} = 2.3 \text{ V to } 3. \\ V_{CC} = 2.3 \text{ V to } 3. \\ V_{CC} = 3.3 \text{ V to } 3. \\ V_{CC} = 3.4 \text{ V to } 3. \\ V_{CC} = 3.4 \text{ V to } 3. \\ V_{CC} = 4.5 \text{ V to } 3. \\ V_{CC} = 2.3 \text{ V to } 3. \\ V$	V _{CC} = 4.5 V to 5.5 V	V _{CC} × 0.7			
		V _{CC} = 2 V		0.5	
\ <u>\</u>	Low level input veltage	V _{CC} = 2.3 V to 2.7 V		V _{CC} × 0.3	V
V IL	Low-level input voltage	V _{CC} = 3 V to 3.6 V		V _{CC} × 0.3	V
		V _{CC} = 4.5 V to 5.5 V		V _{CC} × 0.3	
VI	Input voltage	·	0	5.5	V
Vo	Output voltage		0	V _{CC}	V
	Output voltage	V _{CC} = 2 V		-50	μΑ
	High level output ourrent	V _{CC} = 2.3 V to 2.7 V		-2	
'ОН	Input voltage Output voltage High-level output current	V _{CC} = 3 V to 3.6 V		-6	mA
		V _{CC} = 4.5 V to 5.5 V		-12	
		V _{CC} = 2 V		50	μΑ
	Low level output ourrent	V _{CC} = 2.3 V to 2.7 V		2	
IOL	Input voltage Output voltage DH High-level output current Low-level output current Lt/Δv Input transition rise or fall rate	V _{CC} = 3 V to 3.6 V		6	mA
		V _{CC} = 4.5 V to 5.5 V		12	
		V _{CC} = 2.3 V to 2.7 V		200	
Δt/Δν	Input transition rise or fall rate	V _{CC} = 3 V to 3.6 V		100	ns/V
İ		V _{CC} = 4.5 V to 5.5 V		20	
T _A	Operating free-air temperature		-40	85	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*.

6.4 Thermal Information

			SN74LV138A						
THERMAL METRIC(1)		D	DB	DGV	NS	PW	RGY	BQB	UNIT
		16 PINS							
R _{θJA}	Junction-to-ambient thermal resistance	73	82	120	64	108	39	86	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see *IC Package Thermal Metrics*.

6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V	SN74L	UNIT		
	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	ONIT
V _{OH} High-Leve		I _{OH} = -50 μA	2 V to 5.5 V	V _{CC} - 0.1			
		I _{OH} = -2 mA	2.3 V	2			
	High-Level Output Voltage	I _{OH} = -6 mA	3 V	2.48			V
		I _{OH} = -12 mA	4.5 V	3.8	,		

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V	SN74LV138A	UNIT
	PARAMETER	TEST CONDITIONS	V _{cc}	MIN TYP MAX	UNII
		I _{OL} = 50 μA	2 V to 5.5 V	0.1	
V _{OL}	Low-Level Output Voltage	I _{OL} = 2 mA	2.3 V	0.4	V
		I _{OL} = 6 mA	3 V	0.44	V
		I _{OL} = 12 mA	4.5 V	0.55	
I _I	Input Current	V _I = 5.5 V or GND	0 to 5.5 V	±1	μΑ
I _{CC}	Supply Current	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	20	μΑ
I _{off}	Input/Output Power-Off Leakage Current	V_{I} or $V_{O} = 0$ to 5.5 V	0	5	μΑ
Ci	Input Capacitance	V _I = V _{CC} or GND	3.3 V	2.1	pF

6.6 Switching Characteristics, $V_{CC} = 2.5 \text{ V} \pm 0.25 \text{ V}$

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM TO		LOAD	T _A = 25°C			SN74L	UNIT	
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	
t _{pd}	A ₀ , A ₁ , A ₂				11.7	17.6	1	21	
	G2	Y	C _L = 15 pF		12.3	19.2	1	22	-
	G0 or G1				11.4	18.2	1	21	
	A ₀ , A ₁ , A ₂		C _L = 50 pF		14.9	21.4	1	25	
t _{pd}	G2	Υ			15.7	22.6	1	26	ns
	G0 or G1				14.8	22	1	25	

6.7 Switching Characteristics, V_{CC} = 3.3 V \pm 0.3 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM	то	TO LOAD CAPACITANCE	T _A = 25°C			SN74L	UNIT	
PARAMETER	(INPUT)	(OUTPUT)		MIN	TYP	MAX	MIN	MAX	UNIT
	A ₀ , A ₁ , A ₂				8.1	11.4	1	13.5	
t _{pd}	G2	Y	C _L = 15 pF		8.4	12.8	1	15	ns
	G0 or G1				7.8	11.4	1	13.5	
	A ₀ , A ₁ , A ₂	Y	C _L = 50 pF		10.3	15.8	1	18	
t _{pd}	G2				10.6	16.3	1	18.5	ns
	G0 or G1				10	14.9	1	17	

6.8 Switching Characteristics, V_{CC} = 5 V ± 0.5 V

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 7-1)

PARAMETER	FROM	то	LOAD CAPACITANCE	T _A = 25°C			SN74L	UNIT	
PARAMETER	(INPUT)	(OUTPUT)		MIN	TYP	MAX	MIN	MAX	
t _{pd}	A ₀ , A ₁ , A ₂				5.6	8.1	1	9.5	
	G2	Y	C _L = 15 pF		5.7	8.1	1	9.5	-
	G0 or G1				5.4	8.1	1	9.5	
	A ₀ , A ₁ , A ₂				7	10.1	1	11.5	
t _{pd}	G2	Y	C _L = 50 pF		7.1	10.1	1	11.5	ns
	G0 or G1				6.8	10.1	1	11.5	

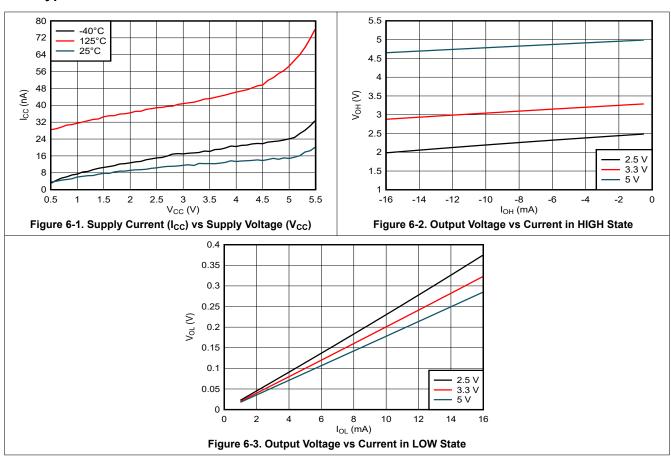


6.9 Operating Characteristics

T_A = 25°C

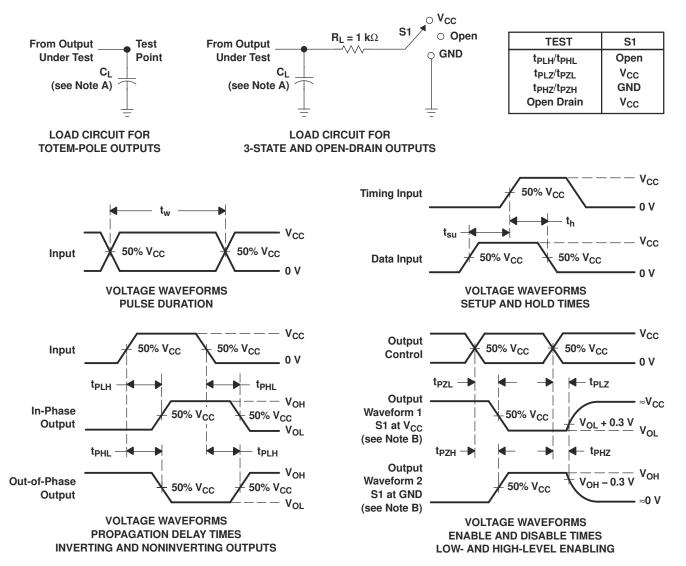
	PARAMETER	TEST CONDITIONS	V _{CC}	TYP	UNIT
C _{pd}	Power discipation canacitance	$C_1 = 50 \text{ pF}, f = 10 \text{ MHz}$	3.3 V	16.8	pF
	Power dissipation capacitance	- οι ρε, τ - το ΜπΖ	5 V	19.1	

6.10 Typical Characteristics





7 Parameter Measurement Information



- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns.
 - D. The outputs are measured one at a time, with one input transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. t_{PZL} and t_{PZH} are the same as t_{en}.
 - G. t_{PHL} and t_{PLH} are the same as t_{pd} .
 - $\mbox{H.}~~\mbox{All parameters and waveforms are not applicable to all devices.}$

Figure 7-1. Load Circuits and Voltage Waveforms

8 Detailed Description

8.1 Overview

The SN74LV138A devices are 3-line to 8-line decoders/demultiplexers designed for 2 V to 5.5 V V_{CC} operation.

These devices are designed for high-performance memory-decoding or data-routing applications requiring very short propagation delay times. In high-performance memory systems, these decoders can be used to minimize the effects of system decoding. When employed with high-speed memories utilizing a fast enable circuit, the delay times of these decoders and the enable time of the memory usually are less than the typical access time of the memory. This means that the effective system delay introduced by the decoder is negligible.

The conditions at the binary-select inputs (A_0, A_1, A_2) and the three enable inputs $(G_2, \overline{G_0}, \overline{G_1})$ select one of eight output lines. The two active-low $(\overline{G_0}, \overline{G_1})$ and one active-high (G_2) enable inputs reduce the need for external gates or inverters when expanding. A 24-line decoder can be implemented without external inverters and a 32-line decoder requires only one inverter. An enable input can be used as a data input for demultiplexing applications.

These devices are fully specified for partial-power-down applications using I_{off}. The I_{off} circuitry disables the outputs, preventing damaging current backflow through the devices when they are powered down.

8.2 Functional Block Diagram

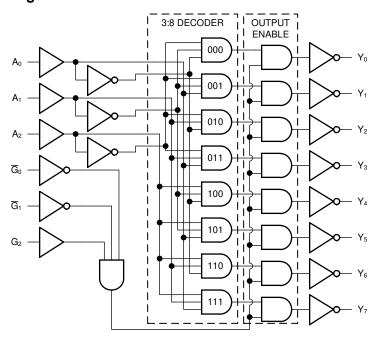


Figure 8-1. Logic Diagram (Positive Logic)

8.3 Feature Description

8.3.1 Standard CMOS Inputs

This device includes standard CMOS inputs. Standard CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings*, and the maximum input leakage current, given in the *Electrical Characteristics*, using Ohm's law $(R = V \div I)$.

Standard CMOS inputs require that input signals transition between valid logic states quickly, as defined by the input transition time or rate in the *Recommended Operating Conditions* table. Failing to meet this specification will result in excessive power consumption and could cause oscillations. More details can be found in *Implications of Slow or Floating CMOS Inputs*.

Do not leave standard CMOS inputs floating at any time during operation. Unused inputs must be terminated at V_{CC} or GND. If a system will not be actively driving an input at all times, then a pull-up or pull-down resistor can be added to provide a valid input voltage during these times. The resistor value will depend on multiple factors; a $10\text{-k}\Omega$ resistor, however, is recommended and will typically meet all requirements.

8.3.2 Balanced CMOS Push-Pull Outputs

This device includes balanced CMOS push-pull outputs. The term *balanced* indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads, so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

Unused push-pull CMOS outputs should be left disconnected.

8.3.3 Partial Power Down (I_{off})

This device includes circuitry to disable all outputs when the supply pin is held at 0 V. When disabled, the outputs will neither source nor sink current, regardless of the input voltages applied. The amount of leakage current at each output is defined by the loff specification in the *Electrical Characteristics* table.

8.3.4 Clamp Diode Structure

Figure 8-2 shows the inputs and outputs to this device have negative clamping diodes only.

CAUTION

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

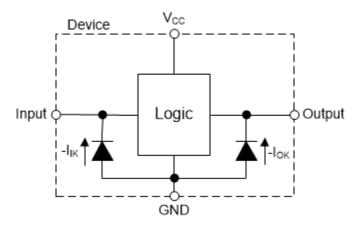


Figure 8-2. Electrical Placement of Clamping Diodes for Each Input and Output

8.4 Device Functional Modes

Function Table

ENABLE INPUTS ⁽¹⁾ SELECT INPUTS				OUTF	OUTPUTS ⁽²⁾								
G2	G0	G1	A ₂	A ₁	A_0	Y0	Y1	Y20	Y3	Y4	Y5	Y6	Y 7
Х	Н	Х	Х	Х	X	Н	Н	Н	Н	Н	Н	Н	Н
X	Χ	Н	Х	Χ	Χ	Н	Н	Н	Н	Н	Н	Н	Н
L	Χ	Χ	Х	Χ	Χ	Н	Н	Н	Н	Н	Н	Н	Н
Н	L	L	L	L	L	L	Н	Н	Н	Н	Н	Н	Н
Н	L	L	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н
Н	L	L	L	Н	L	Н	Н	L	Н	Н	Н	Н	Н



Function Table (continued)

ENA	ENABLE INPUTS(1) SELECT INPUTS					OUTPUTS ⁽²⁾							
G2	G0	G1	A ₂	A ₁	A ₀	Y0	Y1	Y20	Y3	Y4	Y5	Y6	Y7
Н	L	L	L	Н	Н	Н	Н	Н	L	Н	Н	Н	Н
Н	L	L	Н	L	L	Н	Н	Н	Н	L	Н	Н	Н
Н	L	L	Н	L	Н	Н	Н	Н	Н	Н	L	Н	Н
Н	L	L	Н	Н	L	Н	Н	Н	Н	Н	Н	L	Н
Н	L	L	Н	Н	Н	Н	Н	Н	Н	Н	Н	Н	L

- H = High Voltage Level, L = Low Voltage Level, X = Don't Care H = Driving High, L = Driving Low, Z = High Impedance State (2)

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The SN74LV138A is a low drive CMOS device that can be used for a multitude of output expansion applications where output ringing is a concern. The low-drive and slow-edge rates minimize overshoot and undershoot on the outputs.

9.2 Typical Application

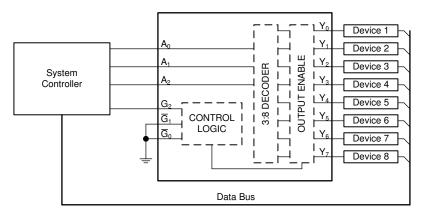


Figure 9-1. Output Exapnsion with Multiplexer

9.2.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74LV138A plus the maximum static supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only source as much current that is provided by the positive supply source. Be sure to not exceed the maximum total current through V_{CC} listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN74LV138A plus the maximum supply current, I_{CC}, listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Be sure to not exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.

The SN74LV138A can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 50 pF.

The SN74LV138A can drive a load with total resistance described by $R_L \ge V_O$ / I_O , with the output voltage and current defined in the *Electrical Characteristics* table with V_{OH} and V_{OL} . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V_{CC} pin.

Total power consumption can be calculated using the information provided in *CMOS Power Consumption and Cpd Calculation*.



Thermal increase can be calculated using the information provided in *Thermal Characteristics of Standard Linear* and Logic (SLL) Packages and Devices.

CAUTION

The maximum junction temperature, $T_{J(max)}$ listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

9.2.2 Input Considerations

Input signals must cross $V_{IL(max)}$ to be considered a logic LOW, and $V_{IH(min)}$ to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either V_{CC} or ground. The unused inputs can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input will be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The drive current of the controller, leakage current into the SN74LV138A (as specified in the *Electrical Characteristics*), and the desired input transition rate limits the resistor size. A 10-k Ω resistor value is often used due to these factors.

The SN74LV138A has CMOS inputs and thus requires fast input transitions to operate correctly, as defined in the *Recommended Operating Conditions* table. Slow input transitions can cause oscillations, additional power consumption, and reduction in device reliability.

Refer to the *Feature Description* section for additional information regarding the inputs for this device.

9.2.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V_{CC} or ground.

Refer to the Feature Description section for additional information regarding the outputs for this device.

9.2.4 Detailed Design Procedure

- Add a decoupling capacitor from V_{CC} to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V_{CC} and GND pins. An example layout is shown in the *Layout* section.
- 2. Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit; it will, however, ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the SN74LV138A to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than $(V_{CC} / I_{O(max)}) \Omega$. This will ensure that the maximum output current from the *Absolute Maximum Ratings* is not violated. Most CMOS inputs have a resistive load measured in M Ω ; much larger than the minimum calculated previously.
- 4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, *CMOS Power Consumption and Cpd Calculation*.

9.2.5 Application Curves

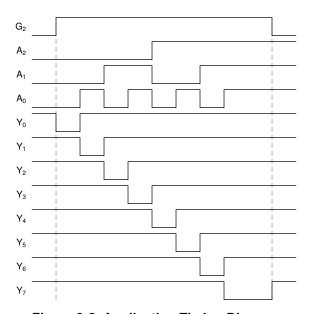


Figure 9-2. Application Timing Diagram

9.3 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Absolute Maximum Ratings* section. Each V_{CC} terminal must have a good bypass capacitor to prevent power disturbance. For devices with a single supply, TI recommends a 0.1- μ F capacitor; if there are multiple V_{CC} terminals, then TI recommends a 0.01- μ F or 0.022- μ F capacitor for each power terminal. Multiple bypass capacitors can be paralleled to reject different frequencies of noise. Frequencies of 0.1 μ F and 1 μ F are commonly used in parallel. The bypass capacitor must be installed as close as possible to the power terminal for best results.

9.4 Layout

9.4.1 Layout Guidelines

When using multiple bit logic devices, inputs should not float. In many cases, functions or parts of functions of digital logic devices are unused. Some examples are when only two inputs of a triple-input AND gate are used, or when only 3 of the 4-buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

9.4.2 Layout Example

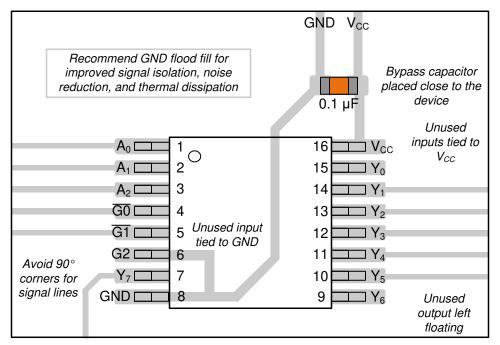


Figure 9-3. Layout Example for the SN74LV138A

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Documentation Support

10.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, CMOS Power Consumption and Cpd Calculation application report
- Texas Instruments, Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices application report

10.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

10.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 11-May-2023

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing		Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
SN74LV138ABQBR	ACTIVE	WQFN	BQB	16	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	LV138A	Samples
SN74LV138ADBR	ACTIVE	SSOP	DB	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV138A	Samples
SN74LV138ADGVR	ACTIVE	TVSOP	DGV	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV138A	Samples
SN74LV138ADR	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV138A	Samples
SN74LV138ANSR	ACTIVE	SO	NS	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	74LV138A	Samples
SN74LV138APWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-40 to 85	LV138A	Samples
SN74LV138APWRG4	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	LV138A	Samples
SN74LV138ARGYR	ACTIVE	VQFN	RGY	16	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	LV138A	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.





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(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74LV138A:

Automotive: SN74LV138A-Q1

NOTE: Qualified Version Definitions:

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects



www.ti.com 9-Dec-2023

TAPE AND REEL INFORMATION



TAPE DIMENSIONS KO PI BO BO Cavity AO

A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter	Reel Width	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	(mm)	Pin1 Quadrant
	Туре	Diawing			(mm)	W1 (mm)	, ,	(11111)	(11111)	(11111)	(11111)	Quadrant
SN74LV138ABQBR	WQFN	BQB	16	3000	180.0	12.4	2.8	3.8	1.2	4.0	12.0	Q1
SN74LV138ADBR	SSOP	DB	16	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
SN74LV138ADGVR	TVSOP	DGV	16	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
SN74LV138ADR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN74LV138ANSR	so	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1
SN74LV138APWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LV138APWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LV138APWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LV138APWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LV138ARGYR	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1



www.ti.com 9-Dec-2023

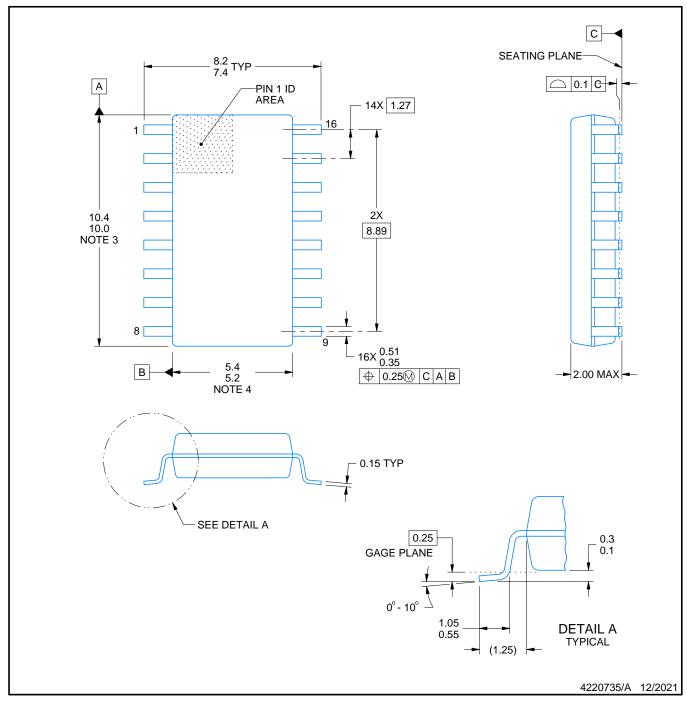


*All dimensions are nominal

7 til dilliciololis are nominal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LV138ABQBR	WQFN	BQB	16	3000	210.0	185.0	35.0
SN74LV138ADBR	SSOP	DB	16	2000	356.0	356.0	35.0
SN74LV138ADGVR	TVSOP	DGV	16	2000	356.0	356.0	35.0
SN74LV138ADR	SOIC	D	16	2500	340.5	336.1	32.0
SN74LV138ANSR	so	NS	16	2000	356.0	356.0	35.0
SN74LV138APWR	TSSOP	PW	16	2000	356.0	356.0	35.0
SN74LV138APWR	TSSOP	PW	16	2000	356.0	356.0	35.0
SN74LV138APWRG4	TSSOP	PW	16	2000	356.0	356.0	35.0
SN74LV138APWRG4	TSSOP	PW	16	2000	356.0	356.0	35.0
SN74LV138ARGYR	VQFN	RGY	16	3000	356.0	356.0	35.0



SOP

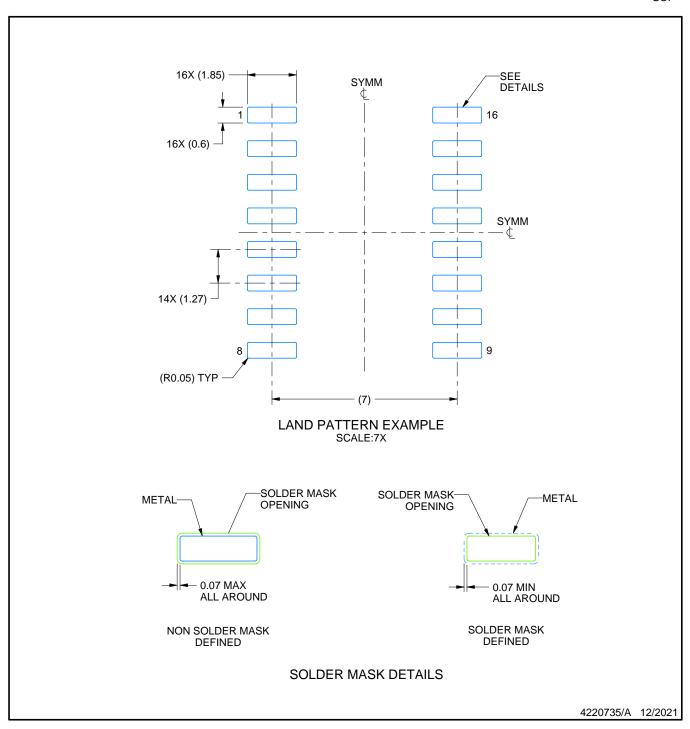


NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm, per side.

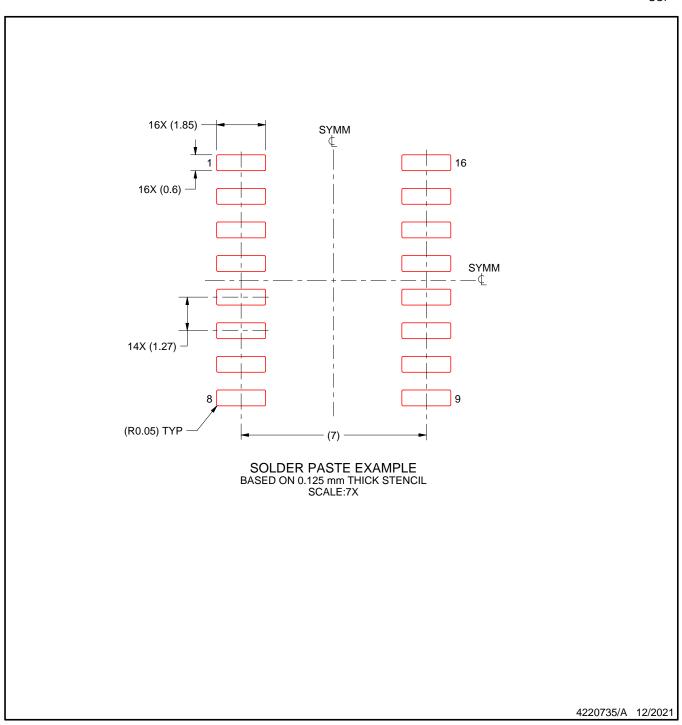
SOF



NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

SOF



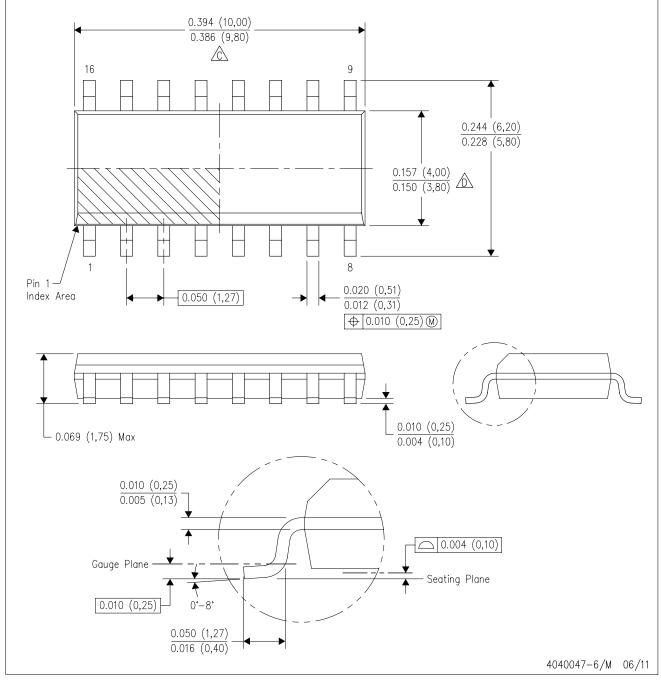
NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE

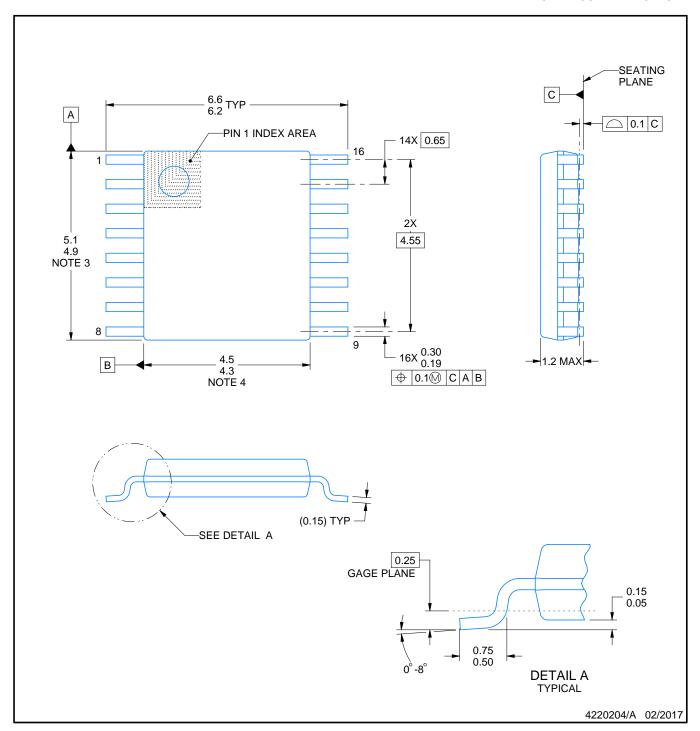


NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.







NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



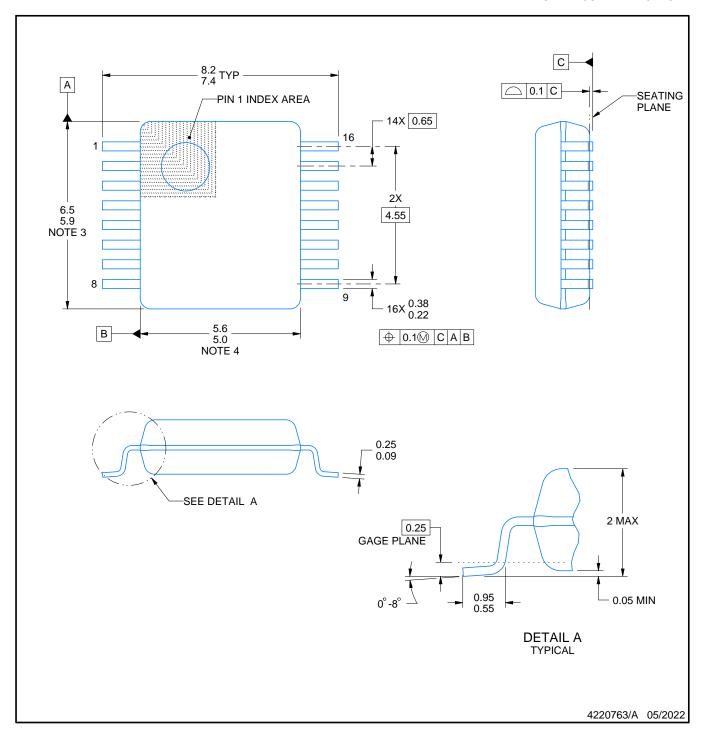


NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







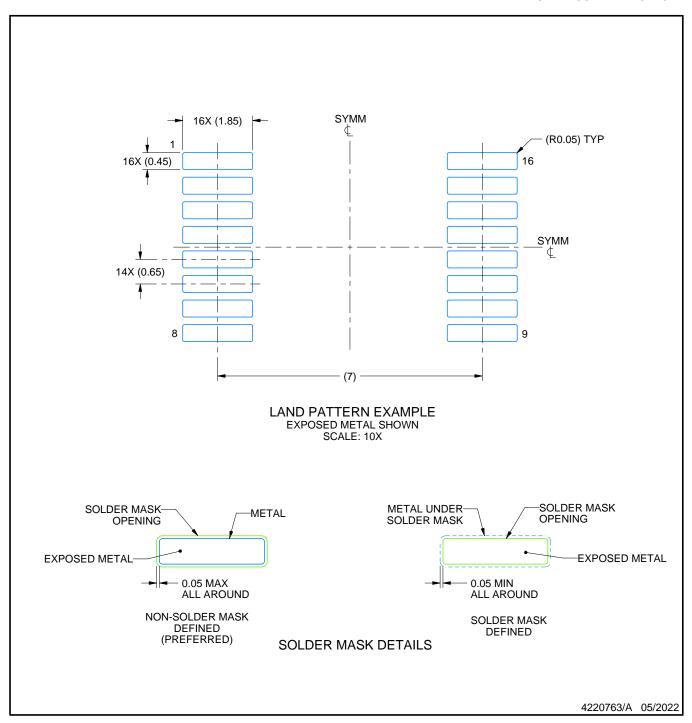
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-150.

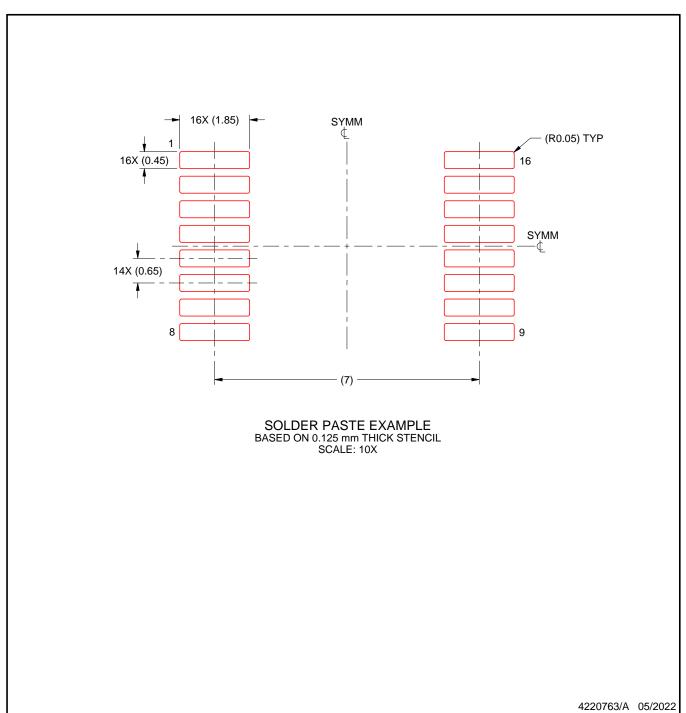




NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



MECHANICAL DATA

NS (R-PDSO-G**)

14-PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



DGV (R-PDSO-G**)

24 PINS SHOWN

PLASTIC SMALL-OUTLINE



NOTES: A. All linear dimensions are in millimeters.

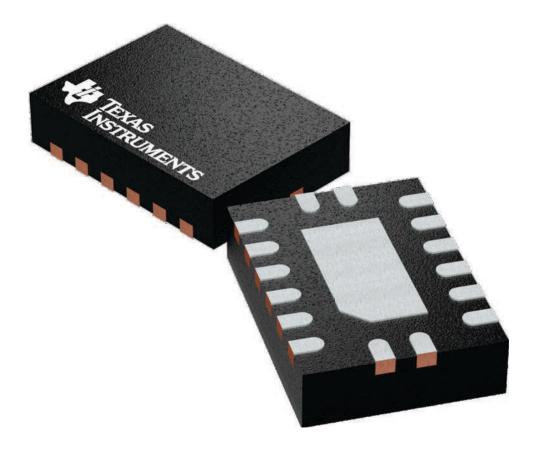
B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.

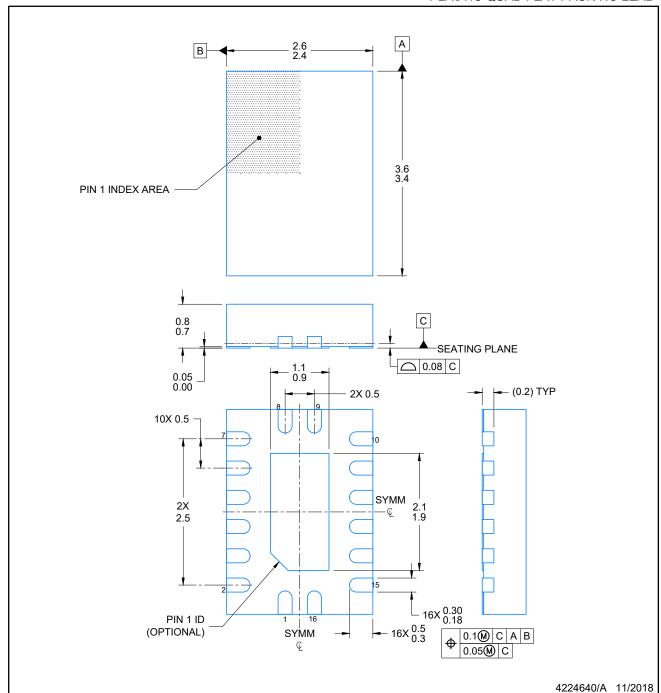
D. Falls within JEDEC: 24/48 Pins – MO-153 14/16/20/56 Pins – MO-194 2.5 x 3.5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



PLASTIC QUAD FLAT PACK-NO LEAD

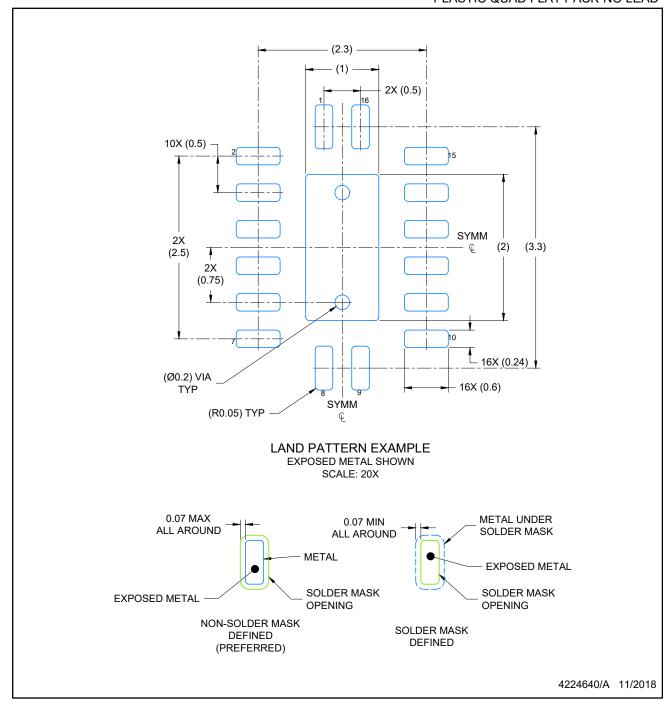


NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



PLASTIC QUAD FLAT PACK-NO LEAD

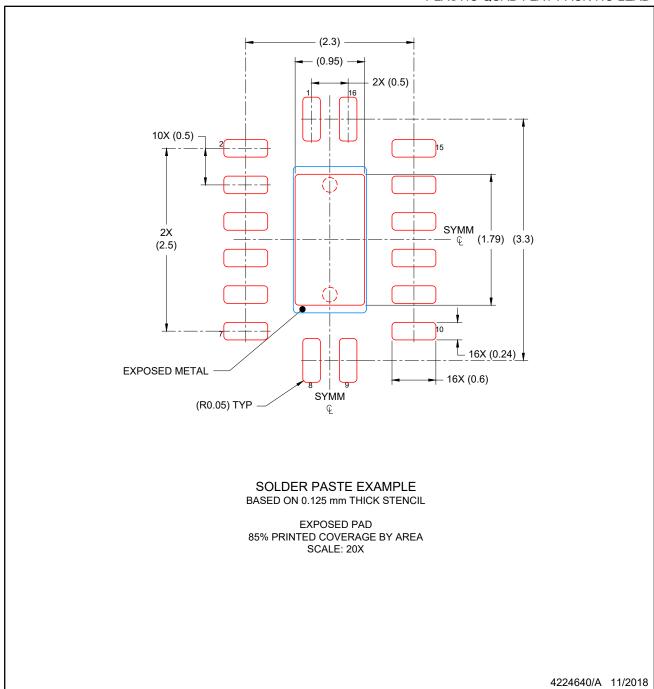


NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



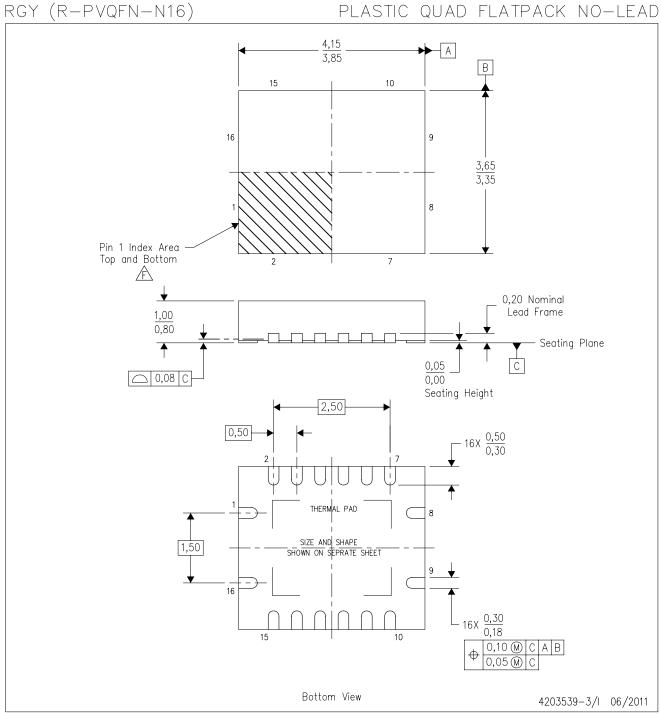
PLASTIC QUAD FLAT PACK-NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



RGY (R-PVQFN-N16)

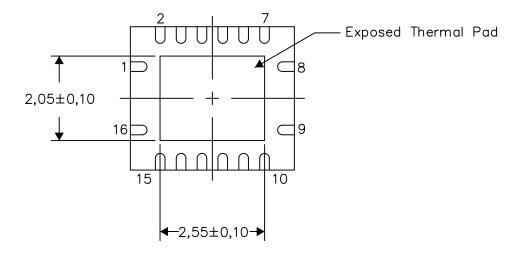
PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

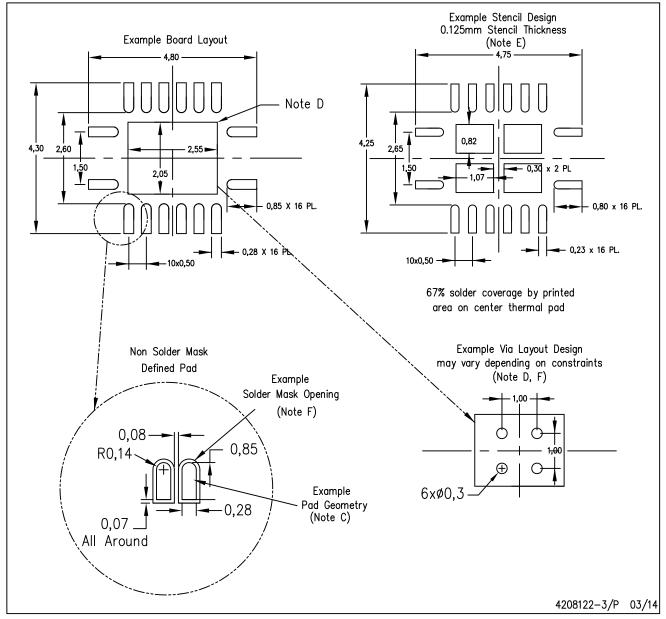
4206353-3/P 03/14

NOTE: All linear dimensions are in millimeters



RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



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>>TI (德州仪器)